



Report No. HTT2025071186CH-1

Test Report

Application information:

Applicant name:	Shenzhen PULUZ Technology Limited
Address:	8/F, 614 Bldg, Bagua 1st Road, Futian, Shenzhen, China
Manufacturer:	Shenzhen PULUZ Technology Limited
Address:	8/F, 614 Bldg, Bagua 1st Road, Futian, Shenzhen, China

Sample information:

Sample Name:	Silicone Band Watch
Sample Model:	XD01,XD02,XD03,XD04,XD05,XD06,XD07,XD08,XD09,XD10,XD11,XD12, XD13,XD14,XD15,XD16,XD17,XD18,XD19,XD20,XD21,XD22,XD23,XD24, XD25,XD26,XD27,XD28,XD29,XD30,XD31,XD32,XD33,XD34,XD35,XD36, XD37,XD38,XD39,XD40,XD41,XD42,XD43,XD44,XD45,XD46,XD47,XD48, XD49,XD50,XD51,XD52,XD53,XD54,XD55,XD56,XD57,XD58,XD59,XD60, XD61,XD62,XD63
Trade mark:	N/A
Sample Received Date:	Jul. 24, 2025
Testing Period:	Jul. 24, 2025 ~ Jul. 30, 2025
Test Requested:	According to the customer's requirements, determine whether the lead, cadmium contents in the submitted samples meet the requirements of REACH Appendix XVII in RSL certification.
Test Method:	Please refer to next page(s).
Test Results	Please refer to next page(s).
Conclusion:	PASS

Completed by:

Reviewed by:

Approved by:

Technical Manager

Shenzhen HTT Technology Co., Ltd.



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1. Test Method(s):

As requested by the client, Reference to IEC 62321-3-1:2013 (Ed1.0) Procedures for the screening analysis of Lead (Pb), Cadmium (Cd), Mercury (Hg), total Chromium (Cr), and Bromine (Br) by XRF. If the screening analysis results exceed the screening limits of IEC 62321-3-1:2013 (Ed1.0) Annex A, use the chemical methods for testing.

Table1 IEC 62321-3-1:2013 (Ed1.0) Annex A screening limits of XRF (mg/kg)

Element	Polymer	Metal	Composite Materials
Cd	$BL \leq (70-3\sigma) < X < (130+3\sigma) \leq OL$	$BL \leq (70-3\sigma) < X < (130+3\sigma) \leq OL$	$LOD < X < (150+3\sigma) \leq OL$
Pb	$BL \leq (700-3\sigma) < X < (1300+3\sigma) \leq OL$	$BL \leq (700-3\sigma) < X < (1300+3\sigma) \leq OL$	$BL \leq (500-3\sigma) < X < (1500+3\sigma) \leq OL$

BL = Less than screening limits of XRF

OL = More than screening limits of XRF

X = The results of screening analysis by XRF are within this range, requiring further chemical testing.

LOD = Limit of Detection

Table2 testing methods & Equipments

Testing Item	Testing Method	Equipment
Screening analysis by XRF		
Lead (Pb), Cadmium (Cd)	IEC 62321-3-1:2013	ED-XRF
Chemical testing		
Lead (Pb)	IEC 62321-5:2013	ICP-OES
Cadmium (Cd)	IEC 62321-5:2013	ICP-OES



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2. Method Detection Limit (MDL):

For XRF screening analysis (mg/kg)

Item	Pb	Cd
Polymer	20	20
Other materials	50	50

For chemical testing (mg/kg)

Item	Cd	Pb
General materials	10	10

3. Requirement (mg/kg):

Restricted substances	Cd	Pb
Limit	100	1000



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4. Test Result(s):

Part No.	Part Description	Restricted Substances	Results (mg/kg)		Conclusion (P/F)
			EDXRF	Chemical testing	
01	Silicone Band	Cd	BL	/	P
		Pb	BL	/	P
02	Metal pin	Cd	BL	/	P
		Pb	BL	/	P

Note:

mg/kg = milligram per kilogram = ppm

N.D. = Not detected (<MDL)

BL=Less than screening limits of XRF

D = DETECTED = Inconclusive

P = PASS

F = FAIL

/ = Not available



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Photo(s) of the sample(s)





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